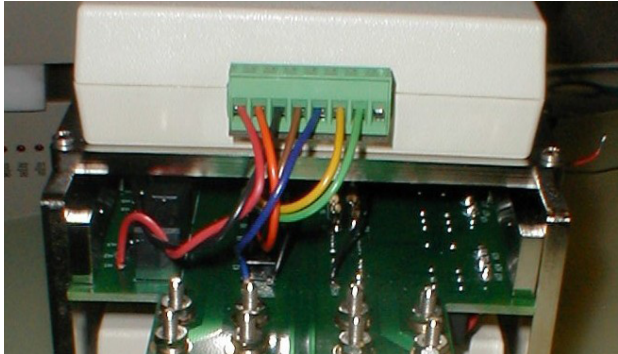
ITC59/55

test site multiplexer



data sheet

overview

The number of tests that can be run on a power semiconductor device as it passes through a test handler during production testing is traditionally limited by the number of test contact positions on the test handler.

Listening to customer input ITC became aware that there is a general requirement to perform more dynamic tests than there are contact sites available on most test handlers.

Working closely with it's customers ITC has been able to develop a multiplexer that allows the ITC55100 UIL test system and the ITC59100 RgQg test system to be connected to one test contact position.

During one contact socket insertion a device can now be avalanche tested and its gate charge, Rdson and gate resistance can also be measured.

In the most common configuration the ITC59000 test platform is the controller for switching the multiplexer and for determining the overall test result which is passed back to the test handler.

Other configurations are available if required.

features

- UIL, Rg, Qg tests all performed on the same contact site
- No degradation of test performance
- Minimal switching time between tests
- Full datalog or simple bin result options available
- Dual or single DUT configurations

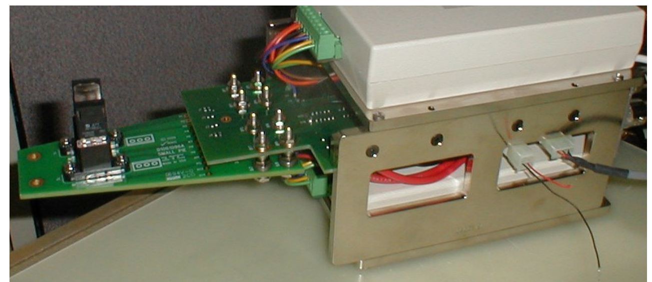
configurations

Options:

- Bin results only/Dual DUT operation - ITC55100 or an ITC5510G and an ITC59000 with two ITC59100 TMUs
- Bin results only/Single DUT operation – ITC55100 or an ITC5510G and an ITC59000 with one ITC59100 TMU

Standard:

- Full datalog/Dual DUT operation - ITC55100 and an ITC59000 with two ITC59100 TMUs
- Full datalog/Single DUT operation – ITC55100 and an ITC59000 with one ITC59100 TMU



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